UNITED STATES PATENT AND TRADEMARK OFFICE



COMMISSIONER FOR PATENTS United States Patent and Trademark Office P.O. Box 1450 ALEXANDRIA, VA 22313-1450 www.uspto.gov

To: Paul Sacher	From: David E Graybill			
Application/Control Number: 10/623,563	Art Unit: 2822 Phone No.: (571)272-1930			
Fax No.: 703-413-2220				
Voice No.:	Return Fax No.: (703) 872-9306			
Re: 10623563	CC:			
Urgent For Review For Comm	ent For Reply Per Your Request			

1449 10-16-03

Number of pages 2 including this page

STATEMENT OF CONFIDENTIALITY

This facsimile transmission is an Official U.S. Government document which may contain information which is privileged and confidential. It is intended only for use of the recipient named above. If you are not the intended recipient, any dissemination, distribution or copying of this document is strictly prohibited. If this document is received in error, you are requested to immediately notify the sender at the above indicated telephone number and return the entire document in an envelope addressed to:

> Commissioner for Patents P.O. Box 1450 Alexandria VA 22313-1450

OT 1 6 2003 &

Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADE OFFICE FRAD			ATTOOCKET NO.		SERIAL NO. 10/623,563					
			2492547US2							
ALL CIONITI										
LIST OF REPERENCES CITED BY APPLICANT			Yukio NISHIDA, et al.							
				FILING DATE		GROUP				
				July 22, 2003						
U.S. PATENT DOCUMENTS										
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE				
(4)	AA	2002/0100945 A1	08/01/2002	J. A. MANDELMAN, et al.	1					
	AB						_			
	AC									
	AD									
	AE									
_	AF									
	AG									
	АН									
	Al	-								
	ĄJ									
	AK									
	AL:									
	AM					 				
	AN					<u> </u>				
			FO.	REIGN PATENT DOCUMENTS		l				
			1	REIGH FATENT DOCUMENTS			. <u>-</u> .			
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO				
9	AO	2002-222947	08/09/2002	JAPAN (with English extract)	APAN (with English extract)		X			
6	AP	2002-305287	10/18/2002	JAPAN (with corr. US 2002/1011945 A1)				· x		
6	AQ	9-82958	03/28/97	JAPAN (with English extract)				×		
•	AR									
	AS									
	AT	•								
	AU				,					
	AV									
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)										
0	AW	T. GHANI, et al., IEDM Technical Digest, pages 415-418, "100 NM GATE LENGTH HIGH PERFORMANCE / LOW POWER CMOS TRANSISTOR STRUCTURE", 1999								
6	AX	T. MATSUMOTO, et al., IEDM Technical Digest, pages 219-222, "70 NM SOI-CMOS OF 135 GHz $f_{\rm max}$ WITH DUAL OFFSET-IMPLANTED SOURCE-DRAIN EXTENSION STRUCTURE FOR RF/ANALOG AND LOGIC APPLICATIONS", 2001								
		K. OTA, et al., Extende	ed Abstracts of	the 2001 International Conference on	Solid State I	Devices and	d Materia	als.		
6	AY	K. OTA, et al., Extended Abstracts of the 2001 International Conference on Solid State Devices and Materials, pages 148-149, "80 NM HIGH PERFORMANCE CMOSFET WITH LOW GATE LEAKAGE CURRENT USING CONVENTIONAL THIN GATE NITRIC OXIDE", 2001								
	AZ	Addition					onal References sheet(s) attached			
Examiner		my			Date Cor	Date Considered 12-20-4				
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										